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Understanding <u>Embedded - FPGAs (Field Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	1176
Number of Logic Elements/Cells	5292
Total RAM Bits	57344
Number of I/O	260
Number of Gates	236666
Voltage - Supply	2.375V ~ 2.625V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	352-LBGA Exposed Pad, Metal
Supplier Device Package	352-MBGA (35x35)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xcv200-4bg352i

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

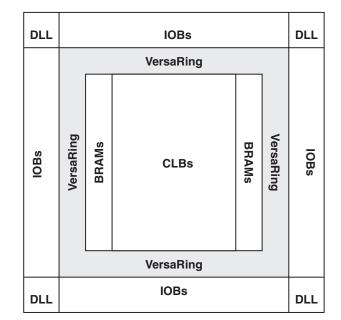


DS003-2 (v4.0) March 1, 2013

Virtex[™] 2.5 V Field Programmable Gate Arrays

Product Specification

The output buffer and all of the IOB control signals have independent polarity controls.



vao_b.eps

Figure 1: Virtex Architecture Overview

All pads are protected against damage from electrostatic discharge (ESD) and from over-voltage transients. Two forms of over-voltage protection are provided, one that permits 5 V compliance, and one that does not. For 5 V compliance, a Zener-like structure connected to ground turns on when the output rises to approximately 6.5 V. When PCI 3.3 V compliance is required, a conventional clamp diode is connected to the output supply voltage, $V_{\rm CCO}$.

Optional pull-up and pull-down resistors and an optional weak-keeper circuit are attached to each pad. Prior to configuration, all pins not involved in configuration are forced into their high-impedance state. The pull-down resistors and the weak-keeper circuits are inactive, but inputs can optionally be pulled up.

The activation of pull-up resistors prior to configuration is controlled on a global basis by the configuration mode pins. If the pull-up resistors are not activated, all the pins will float. Consequently, external pull-up or pull-down resistors must be provided on pins required to be at a well-defined logic level prior to configuration.

All Virtex IOBs support IEEE 1149.1-compatible boundary scan testing.

Architectural Description

Virtex Array

The Virtex user-programmable gate array, shown in Figure 1, comprises two major configurable elements: configurable logic blocks (CLBs) and input/output blocks (IOBs).

- CLBs provide the functional elements for constructing logic
- IOBs provide the interface between the package pins and the CLBs

CLBs interconnect through a general routing matrix (GRM). The GRM comprises an array of routing switches located at the intersections of horizontal and vertical routing channels. Each CLB nests into a VersaBlock™ that also provides local routing resources to connect the CLB to the GRM.

The VersaRing[™] I/O interface provides additional routing resources around the periphery of the device. This routing improves I/O routability and facilitates pin locking.

The Virtex architecture also includes the following circuits that connect to the GRM.

- Dedicated block memories of 4096 bits each
- Clock DLLs for clock-distribution delay compensation and clock domain control
- 3-State buffers (BUFTs) associated with each CLB that drive dedicated segmentable horizontal routing resources

Values stored in static memory cells control the configurable logic elements and interconnect resources. These values load into the memory cells on power-up, and can reload if necessary to change the function of the device.

Input/Output Block

The Virtex IOB, Figure 2, features SelectIO™ inputs and outputs that support a wide variety of I/O signalling standards, see Table 1.

The three IOB storage elements function either as edge-triggered D-type flip-flops or as level sensitive latches. Each IOB has a clock signal (CLK) shared by the three flip-flops and independent clock enable signals for each flip-flop.

In addition to the CLK and CE control signals, the three flip-flops share a Set/Reset (SR). For each flip-flop, this signal can be independently configured as a synchronous Set, a synchronous Reset, an asynchronous Preset, or an asynchronous Clear.

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Input Path

A buffer In the Virtex IOB input path routes the input signal either directly to internal logic or through an optional input flip-flop.

An optional delay element at the D-input of this flip-flop eliminates pad-to-pad hold time. The delay is matched to the internal clock-distribution delay of the FPGA, and when used, assures that the pad-to-pad hold time is zero.

Each input buffer can be configured to conform to any of the low-voltage signalling standards supported. In some of these standards the input buffer utilizes a user-supplied threshold voltage, V_{REF}. The need to supply V_{REF} imposes constraints on which standards can used in close proximity to each other. See I/O Banking, page 3.

There are optional pull-up and pull-down resistors at each user I/O input for use after configuration. Their value is in the range 50 k Ω – 100 k Ω .

Output Path

The output path includes a 3-state output buffer that drives the output signal onto the pad. The output signal can be routed to the buffer directly from the internal logic or through an optional IOB output flip-flop.

The 3-state control of the output can also be routed directly from the internal logic or through a flip-flip that provides synchronous enable and disable.

Each output driver can be individually programmed for a wide range of low-voltage signalling standards. Each output buffer can source up to 24 mA and sink up to 48mA. Drive strength and slew rate controls minimize bus transients.

In most signalling standards, the output High voltage depends on an externally supplied V_{CCO} voltage. The need to supply V_{CCO} imposes constraints on which standards can be used in close proximity to each other. See **I/O Banking**, page 3.

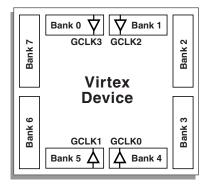
An optional weak-keeper circuit is connected to each output. When selected, the circuit monitors the voltage on the pad and weakly drives the pin High or Low to match the input signal. If the pin is connected to a multiple-source signal, the weak keeper holds the signal in its last state if all drivers are disabled. Maintaining a valid logic level in this way eliminates bus chatter.

Because the weak-keeper circuit uses the IOB input buffer to monitor the input level, an appropriate V_{REF} voltage must be provided if the signalling standard requires one. The provision of this voltage must comply with the I/O banking rules.

I/O Banking

Some of the I/O standards described above require V_{CCO} and/or V_{REF} voltages. These voltages externally and connected to device pins that serve groups of IOBs, called banks. Consequently, restrictions exist about which I/O standards can be combined within a given bank.

Eight I/O banks result from separating each edge of the FPGA into two banks, as shown in Figure 3. Each bank has multiple $V_{\rm CCO}$ pins, all of which must be connected to the same voltage. This voltage is determined by the output standards in use.



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Figure 3: Virtex I/O Banks

Within a bank, output standards can be mixed only if they use the same V_{CCO} . Compatible standards are shown in Table 2. GTL and GTL+ appear under all voltages because their open-drain outputs do not depend on V_{CCO} .

Table 2: Compatible Output Standards

V _{CCO}	Compatible Standards
3.3 V	PCI, LVTTL, SSTL3 I, SSTL3 II, CTT, AGP, GTL, GTL+
2.5 V	SSTL2 I, SSTL2 II, LVCMOS2, GTL, GTL+
1.5 V	HSTL I, HSTL III, HSTL IV, GTL, GTL+

Some input standards require a user-supplied threshold voltage, V_{REF} In this case, certain user-I/O pins are automatically configured as inputs for the V_{REF} voltage. Approximately one in six of the I/O pins in the bank assume this role

The V_{REF} pins within a bank are interconnected internally and consequently only one V_{REF} voltage can be used within each bank. All V_{REF} pins in the bank, however, must be connected to the external voltage source for correct operation.

Within a bank, inputs that require V_{REF} can be mixed with those that do not. However, only one V_{REF} voltage can be used within a bank. Input buffers that use V_{REF} are not 5 V tolerant. LVTTL, LVCMOS2, and PCI 33 MHz 5 V, are 5 V tolerant.

The V_{CCO} and V_{REF} pins for each bank appear in the device Pinout tables and diagrams. The diagrams also show the bank affiliation of each I/O.

Within a given package, the number of V_{REF} and V_{CCO} pins can vary depending on the size of device. In larger devices,



more I/O pins convert to V_{REF} pins. Since these are always a superset of the V_{REF} pins used for smaller devices, it is possible to design a PCB that permits migration to a larger device if necessary. All the V_{REF} pins for the largest device anticipated must be connected to the V_{REF} voltage, and not used for I/O.

In smaller devices, some V_{CCO} pins used in larger devices do not connect within the package. These unconnected pins can be left unconnected externally, or can be connected to the V_{CCO} voltage to permit migration to a larger device if necessary.

In TQ144 and PQ/HQ240 packages, all V_{CCO} pins are bonded together internally, and consequently the same V_{CCO} voltage must be connected to all of them. In the CS144 package, bank pairs that share a side are interconnected internally, permitting four choices for V_{CCO} . In both cases, the V_{REF} pins remain internally connected as eight banks, and can be used as described previously.

Configurable Logic Block

The basic building block of the Virtex CLB is the logic cell (LC). An LC includes a 4-input function generator, carry logic, and a storage element. The output from the function generator in each LC drives both the CLB output and the D input of the flip-flop. Each Virtex CLB contains four LCs, organized in two similar slices, as shown in Figure 4.

Figure 5 shows a more detailed view of a single slice.

In addition to the four basic LCs, the Virtex CLB contains logic that combines function generators to provide functions

of five or six inputs. Consequently, when estimating the number of system gates provided by a given device, each CLB counts as 4.5 LCs.

Look-Up Tables

Virtex function generators are implemented as 4-input look-up tables (LUTs). In addition to operating as a function generator, each LUT can provide a 16 x 1-bit synchronous RAM. Furthermore, the two LUTs within a slice can be combined to create a 16 x 2-bit or 32 x 1-bit synchronous RAM, or a 16x1-bit dual-port synchronous RAM.

The Virtex LUT can also provide a 16-bit shift register that is ideal for capturing high-speed or burst-mode data. This mode can also be used to store data in applications such as Digital Signal Processing.

Storage Elements

The storage elements in the Virtex slice can be configured either as edge-triggered D-type flip-flops or as level-sensitive latches. The D inputs can be driven either by the function generators within the slice or directly from slice inputs, bypassing the function generators.

In addition to Clock and Clock Enable signals, each Slice has synchronous set and reset signals (SR and BY). SR forces a storage element into the initialization state specified for it in the configuration. BY forces it into the opposite state. Alternatively, these signals can be configured to operate asynchronously. All of the control signals are independently invertible, and are shared by the two flip-flops within the slice.

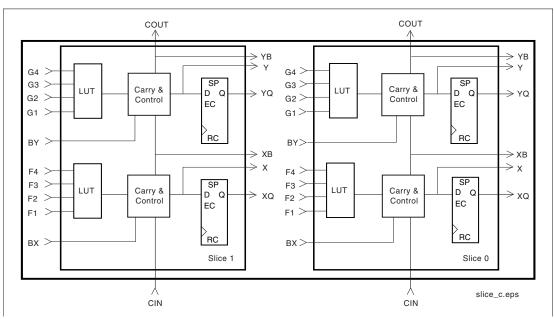


Figure 4: 2-Slice Virtex CLB



General Purpose Routing

Most Virtex signals are routed on the general purpose routing, and consequently, the majority of interconnect resources are associated with this level of the routing hierarchy. The general routing resources are located in horizontal and vertical routing channels associated with the rows and columns CLBs. The general-purpose routing resources are listed below.

- Adjacent to each CLB is a General Routing Matrix (GRM). The GRM is the switch matrix through which horizontal and vertical routing resources connect, and is also the means by which the CLB gains access to the general purpose routing.
- 24 single-length lines route GRM signals to adjacent GRMs in each of the four directions.
- 12 buffered Hex lines route GRM signals to another GRMs six-blocks away in each one of the four directions. Organized in a staggered pattern, Hex lines can be driven only at their endpoints. Hex-line signals can be accessed either at the endpoints or at the midpoint (three blocks from the source). One third of the Hex lines are bidirectional, while the remaining ones are uni-directional.

 12 Longlines are buffered, bidirectional wires that distribute signals across the device quickly and efficiently. Vertical Longlines span the full height of the device, and horizontal ones span the full width of the device.

I/O Routing

Virtex devices have additional routing resources around their periphery that form an interface between the CLB array and the IOBs. This additional routing, called the VersaRing, facilitates pin-swapping and pin-locking, such that logic redesigns can adapt to existing PCB layouts. Time-to-market is reduced, since PCBs and other system components can be manufactured while the logic design is still in progress.

Dedicated Routing

Some classes of signal require dedicated routing resources to maximize performance. In the Virtex architecture, dedicated routing resources are provided for two classes of signal.

- Horizontal routing resources are provided for on-chip 3-state busses. Four partitionable bus lines are provided per CLB row, permitting multiple busses within a row, as shown in Figure 8.
- Two dedicated nets per CLB propagate carry signals vertically to the adjacent CLB.

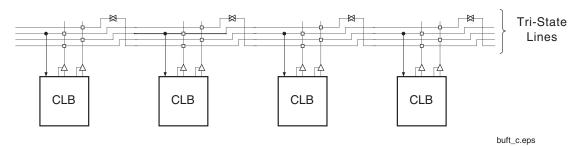


Figure 8: BUFT Connections to Dedicated Horizontal Bus Lines

Global Routing

Global Routing resources distribute clocks and other signals with very high fanout throughout the device. Virtex devices include two tiers of global routing resources referred to as primary global and secondary local clock routing resources.

• The primary global routing resources are four dedicated global nets with dedicated input pins that are designed to distribute high-fanout clock signals with minimal skew. Each global clock net can drive all CLB, IOB, and block RAM clock pins. The primary global nets can only be driven by global buffers. There are four global buffers, one for each global net. The secondary local clock routing resources consist of 24 backbone lines, 12 across the top of the chip and 12 across bottom. From these lines, up to 12 unique signals per column can be distributed via the 12 longlines in the column. These secondary resources are more flexible than the primary resources since they are not restricted to routing only to clock pins.

Clock Distribution

Virtex provides high-speed, low-skew clock distribution through the primary global routing resources described above. A typical clock distribution net is shown in Figure 9.

Four global buffers are provided, two at the top center of the device and two at the bottom center. These drive the four primary global nets that in turn drive any clock pin.



In addition to the test instructions outlined above, the boundary-scan circuitry can be used to configure the FPGA, and also to read back the configuration data.

Figure 10 is a diagram of the Virtex Series boundary scan logic. It includes three bits of Data Register per IOB, the IEEE 1149.1 Test Access Port controller, and the Instruction Register with decodes.

Instruction Set

The Virtex Series boundary scan instruction set also includes instructions to configure the device and read back configuration data (CFG_IN, CFG_OUT, and JSTART). The complete instruction set is coded as shown in Table 5.

Data Registers

The primary data register is the boundary scan register. For each IOB pin in the FPGA, bonded or not, it includes three bits for In, Out, and 3-State Control. Non-IOB pins have appropriate partial bit population if input-only or output-only. Each EXTEST CAPTURED-OR state captures all In, Out, and 3-state pins.

The other standard data register is the single flip-flop BYPASS register. It synchronizes data being passed through the FPGA to the next downstream boundary scan device.

The FPGA supports up to two additional internal scan chains that can be specified using the BSCAN macro. The macro provides two user pins (SEL1 and SEL2) which are decodes of the USER1 and USER2 instructions respectively. For these instructions, two corresponding pins (TDO1 and TDO2) allow user scan data to be shifted out of TDO.

Likewise, there are individual clock pins (DRCK1 and DRCK2) for each user register. There is a common input pin (TDI) and shared output pins that represent the state of the TAP controller (RESET, SHIFT, and UPDATE).

Bit Sequence

The order within each IOB is: In, Out, 3-State. The input-only pins contribute only the In bit to the boundary scan I/O data register, while the output-only pins contributes all three bits.

From a cavity-up view of the chip (as shown in EPIC), starting in the upper right chip corner, the boundary scan data-register bits are ordered as shown in Figure 11.

BSDL (Boundary Scan Description Language) files for Virtex Series devices are available on the Xilinx web site in the File Download area.

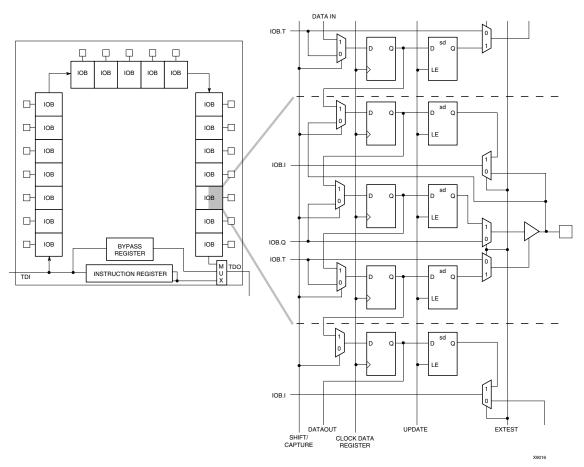


Figure 10: Virtex Series Boundary Scan Logic



ers with a common user interface regardless of their choice of entry and verification tools. The XDM software simplifies the selection of implementation options with pull-down menus and on-line help.

Application programs ranging from schematic capture to Placement and Routing (PAR) can be accessed through the XDM software. The program command sequence is generated prior to execution, and stored for documentation.

Several advanced software features facilitate Virtex design. RPMs, for example, are schematic-based macros with relative location constraints to guide their placement. They help ensure optimal implementation of common functions.

For HDL design entry, the Xilinx FPGA Foundation development system provides interfaces to the following synthesis design environments.

- Synopsys (FPGA Compiler, FPGA Express)
- Exemplar (Spectrum)
- Synplicity (Synplify)

For schematic design entry, the Xilinx FPGA Foundation and alliance development system provides interfaces to the following schematic-capture design environments.

- Mentor Graphics V8 (Design Architect, QuickSim II)
- Viewlogic Systems (Viewdraw)

Third-party vendors support many other environments.

A standard interface-file specification, Electronic Design Interchange Format (EDIF), simplifies file transfers into and out of the development system.

Virtex FPGAs supported by a unified library of standard functions. This library contains over 400 primitives and macros, ranging from 2-input AND gates to 16-bit accumulators, and includes arithmetic functions, comparators, counters, data registers, decoders, encoders, I/O functions, latches, Boolean functions, multiplexers, shift registers, and barrel shifters.

The "soft macro" portion of the library contains detailed descriptions of common logic functions, but does not contain any partitioning or placement information. The performance of these macros depends, therefore, on the partitioning and placement obtained during implementation.

RPMs, on the other hand, do contain predetermined partitioning and placement information that permits optimal implementation of these functions. Users can create their own library of soft macros or RPMs based on the macros and primitives in the standard library.

The design environment supports hierarchical design entry, with high-level schematics that comprise major functional blocks, while lower-level schematics define the logic in these blocks. These hierarchical design elements are automatically combined by the implementation tools. Different design entry tools can be combined within a hierarchical

design, thus allowing the most convenient entry method to be used for each portion of the design.

Design Implementation

The place-and-route tools (PAR) automatically provide the implementation flow described in this section. The partitioner takes the EDIF net list for the design and maps the logic into the architectural resources of the FPGA (CLBs and IOBs, for example). The placer then determines the best locations for these blocks based on their interconnections and the desired performance. Finally, the router interconnects the blocks.

The PAR algorithms support fully automatic implementation of most designs. For demanding applications, however, the user can exercise various degrees of control over the process. User partitioning, placement, and routing information is optionally specified during the design-entry process. The implementation of highly structured designs can benefit greatly from basic floor planning.

The implementation software incorporates Timing Wizard® timing-driven placement and routing. Designers specify timing requirements along entire paths during design entry. The timing path analysis routines in PAR then recognize these user-specified requirements and accommodate them.

Timing requirements are entered on a schematic in a form directly relating to the system requirements, such as the targeted clock frequency, or the maximum allowable delay between two registers. In this way, the overall performance of the system along entire signal paths is automatically tailored to user-generated specifications. Specific timing information for individual nets is unnecessary.

Design Verification

In addition to conventional software simulation, FPGA users can use in-circuit debugging techniques. Because Xilinx devices are infinitely reprogrammable, designs can be verified in real time without the need for extensive sets of software simulation vectors.

The development system supports both software simulation and in-circuit debugging techniques. For simulation, the system extracts the post-layout timing information from the design database, and back-annotates this information into the net list for use by the simulator. Alternatively, the user can verify timing-critical portions of the design using the TRACE® static timing analyzer.

For in-circuit debugging, the development system includes a download and readback cable. This cable connects the FPGA in the target system to a PC or workstation. After downloading the design into the FPGA, the designer can single-step the logic, readback the contents of the flip-flops, and so observe the internal logic state. Simple modifications can be downloaded into the system in a matter of minutes.



Date	Version	Revision
01/00	1.9	Updated DLL Jitter Parameter table and waveforms, added Delay Measurement Methodology table for different I/O standards, changed buffered Hex line info and Input/Output Timing measurement notes.
03/00	2.0	New TBCKO values; corrected FG680 package connection drawing; new note about status of CCLK pin after configuration.
05/00	2.1	Modified "Pins not listed" statement. Speed grade update to Final status.
05/00	2.2	Modified Table 18.
09/00	2.3	 Added XCV400 values to table under Minimum Clock-to-Out for Virtex Devices. Corrected Units column in table under IOB Input Switching Characteristics. Added values to table under CLB SelectRAM Switching Characteristics.
10/00	2.4	 Corrected Pinout information for devices in the BG256, BG432, and BG560 packages in Table 18. Corrected BG256 Pin Function Diagram.
04/01	2.5	 Revised minimums for Global Clock Set-Up and Hold for LVTTL Standard, with DLL. Updated SelectMAP Write Timing Characteristics values in Table 9. Converted file to modularized format. See the Virtex Data Sheet section.
07/19/01	2.6	Made minor edits to text under Configuration.
07/19/02	2.7	Made minor edit to Figure 16 and Figure 18.
09/10/02	2.8	Added clarifications in the Configuration, Boundary-Scan Mode, and Block SelectRAM sections. Revised Figure 17.
12/09/02	2.8.1	 Added clarification in the Boundary Scan section. Corrected number of buffered Hex lines listed in General Purpose Routing section.
03/01/13	4.0	The products listed in this data sheet are obsolete. See XCN10016 for further information.

Virtex Data Sheet

The Virtex Data Sheet contains the following modules:

- DS003-1, Virtex 2.5V FPGAs: Introduction and Ordering Information (Module 1)
- DS003-2, Virtex 2.5V FPGAs: Functional Description (Module 2)

- DS003-3, Virtex 2.5V FPGAs:
 DC and Switching Characteristics (Module 3)
- DS003-4, Virtex 2.5V FPGAs: Pinout Tables (Module 4)



Virtex DC Characteristics

Absolute Maximum Ratings

Symbol	Description ⁽¹⁾			Units
V _{CCINT}	Supply voltage relative to GND ⁽²⁾		-0.5 to 3.0	V
V _{CCO}	Supply voltage relative to GND ⁽²⁾	Supply voltage relative to GND ⁽²⁾		V
V _{REF}	Input Reference Voltage	-0.5 to 3.6	V	
V	Input voltage relative to GND ⁽³⁾	Using V _{REF}	-0.5 to 3.6	V
V _{IN}		Internal threshold	-0.5 to 5.5	V
V _{TS}	Voltage applied to 3-state output		-0.5 to 5.5	V
V _{CC}	Longest Supply Voltage Rise Time from 1V-2.375V		50	ms
T _{STG}	Storage temperature (ambient)		-65 to +150	°C
TJ	Junction temperature ⁽⁴⁾	Plastic Packages	+125	°C

Notes:

- Stresses beyond those listed under Absolute Maximum Ratings can cause permanent damage to the device. These are stress
 ratings only, and functional operation of the device at these or any other conditions beyond those listed under Operating Conditions
 is not implied. Exposure to Absolute Maximum Ratings conditions for extended periods of time can affect device reliability.
- 2. Power supplies can turn on in any order.
- 3. For protracted periods (e.g., longer than a day), V_{IN} should not exceed V_{CCO} by more than 3.6 V.
- 4. For soldering guidelines and thermal considerations, see the "Device Packaging" information on www.xilinx.com.

Recommended Operating Conditions

Symbol	Description		Min	Max	Units
V _{CCINT} ⁽¹⁾	Input Supply voltage relative to GND, $T_J = 0$ °C to +85°C	Commercial	2.5 – 5%	2.5 + 5%	V
CCINT` /	Input Supply voltage relative to GND, $T_J = -40^{\circ}\text{C}$ to $+100^{\circ}\text{C}$	Industrial	2.5 – 5%	2.5 + 5%	V
V _{CCO} ⁽⁴⁾	Supply voltage relative to GND, T _J = 0 °C to +85°C	Commercial	1.4	3.6	V
, CCO,	Supply voltage relative to GND, $T_J = -40^{\circ}C$ to $+100^{\circ}C$	Industrial	1.4	3.6	V
T _{IN}	Input signal transition time			250	ns

- Correct operation is guaranteed with a minimum V_{CCINT} of 2.375 V (Nominal V_{CCINT} -5%). Below the minimum value, all delay parameters increase by 3% for each 50-mV reduction in V_{CCINT} below the specified range.
- 2. At junction temperatures above those listed as Operating Conditions, delay parameters do increase. Please refer to the TRCE report.
- 3. Input and output measurement threshold is \sim 50% of V_{CC} .
- Min and Max values for V_{CCO} are I/O Standard dependant.



DC Characteristics Over Recommended Operating Conditions

Symbol	Description	1	Device	Min	Max	Units
V _{DRINT}	Data Retention V _{CCINT} Voltage		All	2.0		V
21	(below which configuration data can be	e lost)				
V_{DRIO}	Data Retention V _{CCO} Voltage (below which configuration data can be	e lost)	All	1.2		V
I _{CCINTQ}	Quiescent V _{CCINT} supply current ^(1,3)		XCV50		50	mA
			XCV100		50	mA
			XCV150		50	mA
			XCV200		75	mA
			XCV300		75	mA
			XCV400		75	mA
			XCV600		100	mA
			XCV800		100	mA
			XCV1000		100	mA
Iccoq	Quiescent V _{CCO} supply current ⁽¹⁾		XCV50		2	mA
			XCV100		2	mA
			XCV150		2	mA
			XCV200		2	mA
			XCV300		2	mA
			XCV400		2	mA
			XCV600		2	mA
			XCV800		2	mA
			XCV1000		2	mA
I _{REF}	V _{REF} current per V _{REF} pin		All		20	μΑ
ΙL	Input or output leakage current		All	-10	+10	μΑ
C _{IN}	Input capacitance (sample tested)	BGA, PQ, HQ, packages	All		8	pF
I _{RPU}	Pad pull-up (when selected) @ V _{in} = 0 tested)	V, V _{CCO} = 3.3 V (sample	All	Note (2)	0.25	mA
I _{RPD}	Pad pull-down (when selected) @ V _{in} =	= 3.6 V (sample tested)		Note (2)	0.15	mA

- 1. With no output current loads, no active input pull-up resistors, all I/O pins 3-stated and floating.
- 2. Internal pull-up and pull-down resistors guarantee valid logic levels at unconnected input pins. These pull-up and pull-down resistors do not guarantee valid logic levels when input pins are connected to other circuits.
- 3. Multiply I_{CCINTQ} limit by two for industrial grade.



Power-On Power Supply Requirements

Xilinx FPGAs require a certain amount of supply current during power-on to insure proper device operation. The actual current consumed depends on the power-on ramp rate of the power supply. This is the time required to reach the nominal power supply voltage of the device⁽¹⁾ from 0 V. The current is highest at the fastest suggested ramp rate (0 V to nominal voltage in 2 ms) and is lowest at the slowest allowed ramp rate (0 V to nominal voltage in 50 ms). For more details on power supply requirements, see Application Note XAPP158 on www.xilinx.com.

Product	Description ⁽²⁾	Current Requirement ^(1,3)
Virtex Family, Commercial Grade	Minimum required current supply	500 mA
Virtex Family, Industrial Grade	Minimum required current supply	2 A

Notes:

- Ramp rate used for this specification is from 0 2.7 VDC. Peak current occurs on or near the internal power-on reset threshold of 1.0V and lasts for less than 3 ms.
- Devices are guaranteed to initialize properly with the minimum current available from the power supply as noted above.
- 3. Larger currents can result if ramp rates are forced to be faster.

DC Input and Output Levels

Values for V_{IL} and V_{IH} are recommended input voltages. Values for I_{OL} and I_{OH} are guaranteed output currents over the recommended operating conditions at the V_{OL} and V_{OH} test points. Only selected standards are tested. These are chosen to ensure that all standards meet their specifications. The selected standards are tested at minimum V_{CCO} for each standard with the respective V_{OL} and V_{OH} voltage levels shown. Other standards are sample tested.

Input/Output	V _{IL}		V _{IL} V _{IH} V _{OL}		V _{OL}	V _{OH}	I _{OL}	I _{OH}
Standard	V, min	V, max	V, min	V, max	V, Max	V, Min	mA	mA
LVTTL ⁽¹⁾	- 0.5	0.8	2.0	5.5	0.4	2.4	24	-24
LVCMOS2	- 0.5	.7	1.7	5.5	0.4	1.9	12	-12
PCI, 3.3 V	- 0.5	44% V _{CCINT}	60% V _{CCINT}	V _{CCO} + 0.5	10% V _{CCO}	90% V _{CCO}	Note 2	Note 2
PCI, 5.0 V	- 0.5	0.8	2.0	5.5	0.55	2.4	Note 2	Note 2
GTL	- 0.5	V _{REF} - 0.05	V _{REF} + 0.05	3.6	0.4	n/a	40	n/a
GTL+	- 0.5	V _{REF} – 0.1	V _{REF} + 0.1	3.6	0.6	n/a	36	n/a
HSTL I ⁽³⁾	- 0.5	V _{REF} – 0.1	V _{REF} + 0.1	3.6	0.4	V _{CCO} - 0.4	8	-8
HSTL III	- 0.5	V _{REF} – 0.1	V _{REF} + 0.1	3.6	0.4	V _{CCO} - 0.4	24	-8
HSTL IV	- 0.5	V _{REF} – 0.1	V _{REF} + 0.1	3.6	0.4	V _{CCO} - 0.4	48	-8
SSTL3 I	- 0.5	V _{REF} - 0.2	V _{REF} + 0.2	3.6	V _{REF} - 0.6	V _{REF} + 0.6	8	-8
SSTL3 II	- 0.5	V _{REF} - 0.2	V _{REF} + 0.2	3.6	V _{REF} - 0.8	V _{REF} + 0.8	16	-16
SSTL2 I	- 0.5	V _{REF} - 0.2	V _{REF} + 0.2	3.6	V _{REF} - 0.61	V _{REF} + 0.61	7.6	-7.6
SSTL2 II	- 0.5	V _{REF} - 0.2	V _{REF} + 0.2	3.6	V _{REF} - 0.80	V _{REF} + 0.80	15.2	-15.2
CTT	- 0.5	V _{REF} - 0.2	V _{REF} + 0.2	3.6	V _{REF} - 0.4	V _{REF} + 0.4	8	-8
AGP	- 0.5	V _{REF} - 0.2	V _{REF} + 0.2	3.6	10% V _{CCO}	90% V _{CCO}	Note 2	Note 2

- V_{OL} and V_{OH} for lower drive currents are sample tested.
- 2. Tested according to the relevant specifications.
- DC input and output levels for HSTL18 (HSTL I/O standard with V_{CCO} of 1.8 V) are provided in an HSTL white paper on www.xilinx.com.



CLB SelectRAM Switching Characteristics

			Speed			
Description	Symbol	Min	-6	-5	-4	Units
Sequential Delays						
Clock CLK to X/Y outputs (WE active) 16 x 1 mode	T _{SHCKO16}	1.2	2.3	2.6	3.0	ns, max
Clock CLK to X/Y outputs (WE active) 32 x 1 mode	T _{SHCKO32}	1.2	2.7	3.1	3.5	ns, max
Shift-Register Mode						
Clock CLK to X/Y outputs	T _{REG}	1.2	3.7	4.1	4.7	ns, max
Setup and Hold Times before/after Clock CLK ⁽¹⁾		Se	tup Time /	Hold Time	T.	·
F/G address inputs	T _{AS} /T _{AH}	0.25 / 0	0.5 / 0	0.6 / 0	0.7 / 0	ns, min
BX/BY data inputs (DIN)	T _{DS} /T _{DH}	0.34 / 0	0.7 / 0	0.8 / 0	0.9 / 0	ns, min
CE input (WE)	T _{WS} /T _{WH}	0.38 / 0	0.8 / 0	0.9 / 0	1.0 / 0	ns, min
Shift-Register Mode		1		,	1	1
BX/BY data inputs (DIN)	T _{SHDICK}	0.34	0.7	0.8	0.9	ns, min
CE input (WS)	T _{SHCECK}	0.38	0.8	0.9	1.0	ns, min
Clock CLK		-			1	1
Minimum Pulse Width, High	T _{WPH}	1.2	2.4	2.7	3.1	ns, min
Minimum Pulse Width, Low	T _{WPL}	1.2	2.4	2.7	3.1	ns, min
Minimum clock period to meet address write cycle time	T _{WC}	2.4	4.8	5.4	6.2	ns, min
Shift-Register Mode						
Minimum Pulse Width, High	T _{SRPH}	1.2	2.4	2.7	3.1	ns, min
Minimum Pulse Width, Low	T _{SRPL}	1.2	2.4	2.7	3.1	ns, min

^{1.} A Zero "0" Hold Time listing indicates no hold time or a negative hold time. Negative values can not be guaranteed "best-case", but if a "0" is listed, there is no positive hold time.



Block RAM Switching Characteristics

	Speed Grade					
Description	Symbol	Min	-6	-5	-4	Units
Sequential Delays						
Clock CLK to DOUT output	T _{BCKO}	1.7	3.4	3.8	4.3	ns, max
Setup and Hold Times before/after Clock CLK ⁽¹⁾		Setu	p Time / H	old Time		
ADDR inputs	T _{BACK} /T _{BCKA}	0.6 / 0	1.2 / 0	1.3 / 0	1.5 / 0	ns, min
DIN inputs	T _{BDCK} /T _{BCKD}	0.6 / 0	1.2 / 0	1.3 / 0	1.5 / 0	ns, min
EN input	T _{BECK} /T _{BCKE}	1.3 / 0	2.6 / 0	3.0 / 0	3.4 / 0	ns, min
RST input	T _{BRCK} /T _{BCKR}	1.3 / 0	2.5 / 0	2.7 / 0	3.2 / 0	ns, min
WEN input	T _{BWCK} /T _{BCKW}	1.2 / 0	2.3 / 0	2.6 / 0	3.0 / 0	ns, min
Clock CLK						
Minimum Pulse Width, High	T _{BPWH}	0.8	1.5	1.7	2.0	ns, min
Minimum Pulse Width, Low	T _{BPWL}	0.8	1.5	1.7	2.0	ns, min
CLKA -> CLKB setup time for different ports	T _{BCCS}		3.0	3.5	4.0	ns, min

Notes:

TBUF Switching Characteristics

		Speed Grade				
Description	Symbol	Min	-6	-5	-4	Units
Combinatorial Delays						
IN input to OUT output	T _{IO}	0	0	0	0	ns, max
TRI input to OUT output high-impedance	T _{OFF}	0.05	0.09	0.10	0.11	ns, max
TRI input to valid data on OUT output	T _{ON}	0.05	0.09	0.10	0.11	ns, max

JTAG Test Access Port Switching Characteristics

Description	Symbol	-6	-5	-4	Units
TMS and TDI Setup times before TCK	T _{TAPTCK}	4.0	4.0	4.0	ns, min
TMS and TDI Hold times after TCK	T _{TCKTAP}	2.0	2.0	2.0	ns, min
Output delay from clock TCK to output TDO	T _{TCKTDO}	11.0	11.0	11.0	ns, max
Maximum TCK clock frequency	F _{TCK}	33	33	33	MHz, max

^{1.} A Zero "0" Hold Time listing indicates no hold time or a negative hold time. Negative values can not be guaranteed "best-case", but if a "0" is listed, there is no positive hold time.



Table 2: Virtex Pinout Tables (Chip-Scale and QFP Packages) (Continued)

Pin Name	Device	CS144	TQ144	PQ/HQ240
V _{REF} , Bank 3	XCV50	H11, K12	60, 68	130, 144
(V _{REF} pins are listed	XCV100/150	+ J10	+ 66	+ 133
incrementally. Connect all pins listed for both	XCV200/300	N/A	N/A	+ 126
the required device	XCV400	N/A	N/A	+ 147
and all smaller devices listed in the same	XCV600	N/A	N/A	+ 132
package.)	XCV800	N/A	N/A	+ 140
Within each bank, if input reference voltage is not required, all V _{REF} pins are general I/O.				
V _{REF} , Bank 4	XCV50	L8, L10	79, 87	97, 111
(V _{REF} pins are listed	XCV100/150	+ N10	+ 81	+ 108
incrementally. Connect all pins listed for both	XCV200/300	N/A	N/A	+ 115
the required device and all smaller devices	XCV400	N/A	N/A	+ 94
listed in the same	XCV600	N/A	N/A	+ 109
package.)	XCV800	N/A	N/A	+ 101
Within each bank, if input reference voltage is not required, all V _{REF} pins are general I/O.				
V _{REF} , Bank 5	XCV50	L4, L6	96, 104	70, 84
(V _{REF} pins are listed	XCV100/150	+ N4	+ 102	+ 73
incrementally. Connect all pins listed for both	XCV200/300	N/A	N/A	+ 66
the required device	XCV400	N/A	N/A	+ 87
and all smaller devices listed in the same package.)	XCV600	N/A	N/A	+ 72
	XCV800	N/A	N/A	+ 80
Within each bank, if input reference voltage is not required, all V _{REF} pins are general I/O.				



Table 2: Virtex Pinout Tables (Chip-Scale and QFP Packages) (Continued)

Pin Name	Device	CS144	TQ144	PQ/HQ240
V _{REF} , Bank 6	XCV50	H2, K1	116, 123	36, 50
(V _{REF} pins are listed	XCV100/150	+ J3	+ 118	+ 47
incrementally. Connect all pins listed for both	XCV200/300	N/A	N/A	+ 54
the required device	XCV400	N/A	N/A	+ 33
and all smaller devices listed in the same	XCV600	N/A	N/A	+ 48
package.)	XCV800	N/A	N/A	+ 40
Within each bank, if input reference voltage is not required, all V _{REF} pins are general I/O.				
V _{REF} , Bank 7	XCV50	D4, E1	133, 140	9, 23
(V _{REF} pins are listed	XCV100/150	+ D2	+ 138	+ 12
incrementally. Connect all pins listed for both the required device and all smaller devices listed in the same	XCV200/300	N/A	N/A	+ 5
	XCV400	N/A	N/A	+ 26
	XCV600	N/A	N/A	+ 11
package.)	XCV800	N/A	N/A	+ 19
Within each bank, if input reference voltage is not required, all V _{REF} pins are general I/O.				
GND	All	A1, B9, B11, C7, D5, E4, E11, F1, G10, J1, J12, L3, L5, L7, L9, N12	9, 18, 26, 35, 46, 54, 64, 75, 83, 91, 100, 111, 120, 129, 136, 144,	1, 8, 14, 22, 29, 37, 45, 51, 59, 69, 75, 83, 91, 98, 106, 112, 119, 129, 135, 143, 151, 158, 166, 172, 182, 190, 196, 204, 211, 219, 227, 233



Table 3: Virtex Pinout Tables (BGA)

Pin Name	Device	BG256	BG352	BG432	BG560
GCK0	All	Y11	AE13	AL16	AL17
GCK1	All	Y10	AF14	AK16	AJ17
GCK2	All	A10	B14	A16	D17
GCK3	All	B10	D14	D17	A17
MO	All	Y1	AD24	AH28	AJ29
M1	All	U3	AB23	AH29	AK30
M2	All	W2	AC23	AJ28	AN32
CCLK	All	B19	C3	D4	C4
PROGRAM	All	Y20	AC4	АН3	AM1
DONE	All	W19	AD3	AH4	AJ5
INIT	All	U18	AD2	AJ2	AH5
BUSY/DOUT	All	D18	E4	D3	D4
D0/DIN	All	C19	D3	C2	E4
D1	All	E20	G1	K4	K3
D2	All	G19	J3	K2	L4
D3	All	J19	M3	P4	P3
D4	All	M19	R3	V4	W4
D5	All	P19	U4	AB1	AB5
D6	All	T20	V3	AB3	AC4
D7	All	V19	AC3	AG4	AJ4
WRITE	All	A19	D5	B4	D6
CS	All	B18	C4	D5	A2
TDI	All	C17	В3	В3	D5
TDO	All	A20	D4	C4	E6
TMS	All	D3	D23	D29	B33
TCK	All	A1	C24	D28	E29
DXN	All	W3	AD23	AH27	AK29
DXP	All	V4	AE24	AK29	AJ28



Table 3: Virtex Pinout Tables (BGA) (Continued)

Pin Name	Device	BG256	BG352	BG432	BG560
V _{REF} , Bank 3	XCV50	M18, V20	N/A	N/A	N/A
(V _{REF} pins are listed	XCV100/150	+ R19	R4, V4, Y3	N/A	N/A
incrementally. Connect all pins listed for both the required device and all	XCV200/300	+ P18	+ AC2	V2, AB4, AD4, AF3	N/A
smaller devices listed in the	XCV400	N/A	N/A	+ U2	V4, W5,
same package.)					AD3, AE5, AK2
Within each bank, if input reference voltage is not	XCV600	N/A	N/A	+ AC3	+ AF1
required, all V _{REF} pins are	XCV800	N/A	N/A	+ Y3	+ AA4
general I/O.	XCV1000	N/A	N/A	N/A	+ AH4
V _{REF} , Bank 4	XCV50	V12, Y18	N/A	N/A	N/A
(V _{REF} pins are listed incrementally. Connect all	XCV100/150	+ W15	AC12, AE5, AE8,	N/A	N/A
pins listed for both the required device and all smaller devices listed in the	XCV200/300	+ V14	+ AE4	AJ7, AL4, AL8, AL13	N/A
same package.) Within each bank, if input reference voltage is not	XCV400	N/A	N/A	+ AK15	AL7, AL10, AL16, AM4, AM14
required, all V _{REF} pins are	XCV600	N/A	N/A	+ AK8	+ AL9
general I/O.	XCV800	N/A	N/A	+ AJ12	+ AK13
	XCV1000	N/A	N/A	N/A	+ AN3
V _{REF} , Bank 5	XCV50	V9, Y3	N/A	N/A	N/A
(V _{REF} pins are listed incrementally. Connect all pins listed for both the	XCV100/150	+ W6	AC15, AC18, AD20	N/A	N/A
required device and all smaller devices listed in the	XCV200/300	+ V7	+ AE23	AJ18, AJ25, AK23, AK27	N/A
within each bank, if input reference voltage is not	XCV400	N/A	N/A	+ AJ17	AJ18, AJ25, AL20, AL24, AL29
required, all V _{REF} pins are general I/O.	XCV600	N/A	N/A	+ AL24	+ AM26
	XCV800	N/A	N/A	+ AH19	+ AN23
	XCV1000	N/A	N/A	N/A	+ AK28
V _{REF} , Bank 6	XCV50	M2, R3	N/A	N/A	N/A
(V _{REF} pins are listed incrementally. Connect all	XCV100/150	+ T1	R24, Y26, AA25,	N/A	N/A
pins listed for both the required device and all smaller devices listed in the	XCV200/300	+ T3	+ AD26	V28, AB28, AE30, AF28	N/A
same package.) Within each bank, if input	XCV400	N/A	N/A	+ U28	V29, Y32, AD31, AE29, AK32
reference voltage is not	XCV600	N/A	N/A	+ AC28	+ AE31
required, all V _{REF} pins are general I/O.	XCV800	N/A	N/A	+ Y30	+ AA30
general I/O.	XCV1000	N/A	N/A	N/A	+ AH30



Table 4: Virtex Pinout Tables (Fine-Pitch BGA) (Continued)

Pin Name	Device	FG256	FG456	FG676	FG680
V _{CCINT}	All	C3, C14, D4, D13, E5, E12, M5, M12, N4, N13, P3, P14	E5, E18, F6, F17, G7, G8, G9, G14, G15, G16, H7, H16, J7, J16, P7, P16, R7, R16, T7, T8, T9, T14, T15, T16, U6, U17, V5, V18	G7, G20, H8, H19, J9, J10, J11, J16, J17, J18, K9, K18, L9, L18, T9, T18, U9, U18, V9, V10, V11, V16, V17, V18, W8, W19, Y7, Y20	AD5, AD35, AE5, AE35, AL5, AL35, AM5, AM35, AR8, AR9, AR15, AR16, AR24, AR25, AR31, AR32, E8, E9, E15, E16, E24, E25, E31, E32, H5, H35, J5, J35, R5, R35, T5, T35
V _{CCO} , Bank 0	All	E8, F8	F7, F8, F9, F10 G10, G11	H9, H10, H11, H12, J12, J13	E26, E27, E29, E30, E33, E34
V _{CCO} , Bank 1	All	E9, F9	F13, F14, F15, F16, G12, G13	H15, H16, H17, H18, J14, J15	E6, E7, E10, E11, E13, E14
V _{CCO} , Bank 2	All	H11, H12	G17, H17, J17, K16, K17, L16	J19, K19, L19, M18, M19, N18	F5, G5, K5, L5, N5, P5
V _{CCO} , Bank 3	All	J11, J12	M16, N16, N17, P17, R17, T17	P18, R18, R19, T19, U19, V19	AF5, AG5, AN5, AK5, AJ5, AP5
V _{CCO} , Bank 4	All	L9. M9	T12, T13, U13, U14, U15, U16,	V14, V15, W15, W16, W17, W18	AR6, AR7, AR10, AR11, AR13, AR14
V _{CCO} , Bank 5	All	L8, M8	T10, T11, U7, U8, U9, U10	V12, V13, W9,W10, W11, W12	AR26, AR27, AR29, AR30, AR33, AR34
V _{CCO} , Bank 6	All	J5, J6	M7, N6, N7, P6, R6, T6	P9, R8, R9, T8, U8, V8	AF35, AG35, AJ35, AK35, AN35, AP35
V _{CCO} , Bank 7	All	H5, H6	G6, H6, J6, K6, K7, L7	J8, K8, L8, M8, M9, N9	F35, G35, K35, L35, N35, P35
V _{REF} Bank 0	XCV50	B4, B7	N/A	N/A	N/A
(VREF pins are listed	XCV100/150	+ C6	A9, C6, E8	N/A	N/A
incrementally. Connect all pins listed for both	XCV200/300	+ A3	+ B4	N/A	N/A
the required device and all smaller devices listed in the same	XCV400	N/A	N/A	A12, C11, D6, E8, G10	
package.) Within each bank, if	XCV600	N/A	N/A	+ B7	A33, B28, B30, C23, C24, D33
input reference voltage	XCV800	N/A	N/A	+ B10	+ A26
is not required, all V _{REF} pins are general I/O.	XCV1000	N/A	N/A	N/A	+ D34



PQ240/HQ240 Pin Function Diagram

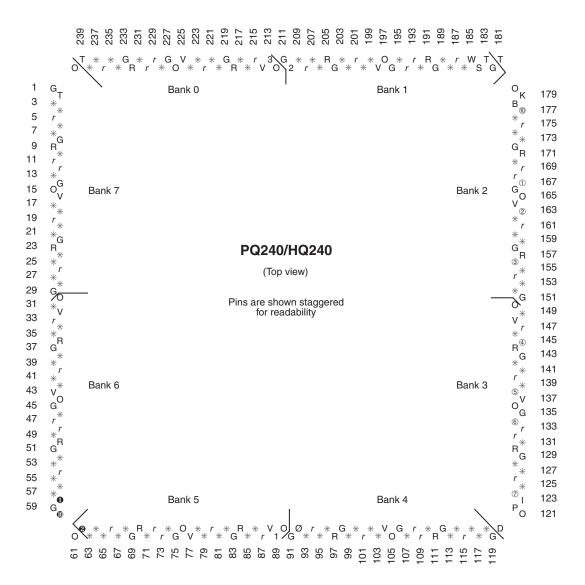


Figure 3: PQ240/HQ240 Pin Function Diagram



FG676 Pin Function Diagram

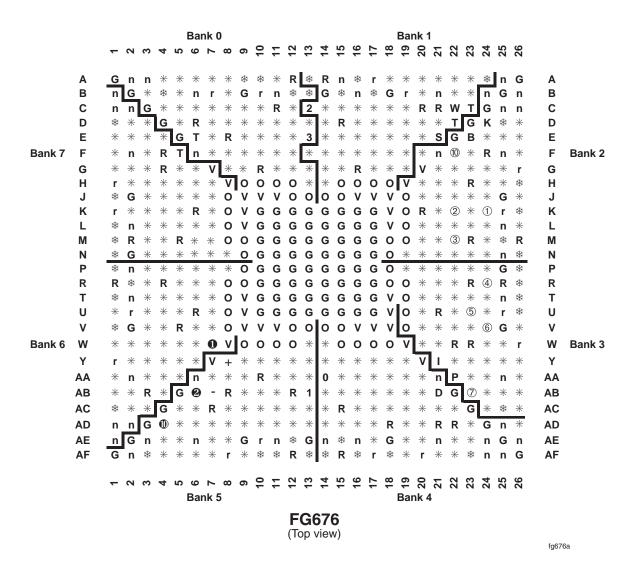


Figure 10: FG676 Pin Function Diagram

Notes:

Packages FG456 and FG676 are layout compatible.



Revision History

Date	Version	Revision			
11/98	1.0	Initial Xilinx release.			
01/99-02/99	1.2-1.3	Both versions updated package drawings and specs.			
05/99	1.4	Addition of package drawings and specifications.			
05/99	1.5	Replaced FG 676 & FG680 package drawings.			
07/99	1.6	Changed Boundary Scan Information and changed Figure 11, Boundary Scan Bit Sequence. Updated IOB Input & Output delays. Added Capacitance info for different I/O Standards. Added 5 V tolerant information. Added DLL Parameters and waveforms and new Pin-to-pin Input and Output Parameter tables for Global Clock Input to Output and Setup and Hold. Changed Configuration Information including Figures 12, 14, 17 & 19. Added device-dependent listings for quiescent currents ICCINTQ and ICCOQ. Updated IOB Input and Output Delays based on default standard of LVTTL, 12 mA, Fast Slew Rate. Added IOB Input Switching Characteristics Standard Adjustments.			
09/99	1.7	Speed grade update to preliminary status, Power-on specification and Clock-to-Out Minimums additions, "0" hold time listing explanation, quiescent current listing update, and Figure 6 ADDRA input label correction. Added T _{IJITCC} parameter, changed T _{OJIT} to T _{OPHASE} .			
01/00	1.8	Update to speed.txt file 1.96. Corrections for CRs 111036,111137, 112697, 115479, 117153, 117154, and 117612. Modified notes for Recommended Operating Conditions (voltage and temperature). Changed Bank information for V _{CCO} in CS144 package on p.43.			
01/00	1.9	Updated DLL Jitter Parameter table and waveforms, added Delay Measurement Methodology table for different I/O standards, changed buffered Hex line info and Input/Output Timing measurement notes.			
03/00	2.0	New TBCKO values; corrected FG680 package connection drawing; new note about status of CCLK pin after configuration.			
05/00	2.1	Modified "Pins not listed" statement. Speed grade update to Final status.			
05/00	2.2	Modified Table 18.			
09/00	2.3	 Added XCV400 values to table under Minimum Clock-to-Out for Virtex Devices. Corrected Units column in table under IOB Input Switching Characteristics. Added values to table under CLB SelectRAM Switching Characteristics. 			
10/00	2.4	 Corrected pinout info for devices in the BG256, BG432, and BG560 pkgs in Table 18. Corrected BG256 Pin Function Diagram. 			
04/02/01	2.5	 Revised minimums for Global Clock Set-Up and Hold for LVTTL Standard, with DLL. Converted file to modularized format. See section Virtex Data Sheet, below. 			
04/19/01	2.6	Corrected pinout information for FG676 device in Table 4. (Added AB22 pin.)			
07/19/01	2.7	 Clarified V_{CCINT} pinout information and added AE19 pin for BG352 devices in Table 3. Changed pinouts listed for BG352 XCV400 devices in banks 0 thru 7. 			
07/19/02	2.8	Changed pinouts listed for GND in TQ144 devices (see Table 2).			
03/01/13	4.0	The products listed in this data sheet are obsolete. See XCN10016 for further information.			

Virtex Data Sheet

The Virtex Data Sheet contains the following modules:

- DS003-1, Virtex 2.5V FPGAs: Introduction and Ordering Information (Module 1)
- DS003-2, Virtex 2.5V FPGAs: Functional Description (Module 2)

- DS003-3, Virtex 2.5V FPGAs: DC and Switching Characteristics (Module 3)
- DS003-4, Virtex 2.5V FPGAs: Pinout Tables (Module 4)